Abstracts

Characterization of Microstrip Discontinuities on Multilayer Dielectric Substrates Including Radiation Losses

W.P. Harokopus, Jr. and P.B. Katehi. "Characterization of Microstrip Discontinuities on Multilayer Dielectric Substrates Including Radiation Losses." 1989 Transactions on Microwave Theory and Techniques 37.12 (Dec. 1989 [T-MTT] (1989 Symposium Issue)): 2058-2066.

A two-dimensional space-domain method of moments treatment of open microstrip discontinuities on multi-dielectric-layer substrates is presented.The full-wave analysis accounts for electromagnetic coupling, radiation, and all substrate effects. The technique has been utilized to characterize commonly used discontinuities on one and two dielectric layers, and numerical results for step, corner, and T-junction discontinuities are included.

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